FAIRCHILD

SEMICONDUCTOR®

FDD86102LZ

N-Channel PowerTrench[®] MOSFET 100 V, 35 A, 22.5 m Ω

Features

- Max $r_{DS(on)}$ = 22.5 m Ω at V_{GS} = 10 V, I_D = 8 A
- Max r_{DS(on)} = 31 mΩ at V_{GS} = 4.5 V, I_D = 7 A
- HBM ESD protection level > 6 kV typical (Note 4)
- Very low Qg and Qgd compared to competing trench technologies
- Fast switching speed
- 100% UIL tested
- RoHS Compliant

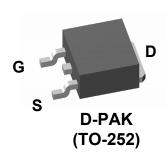


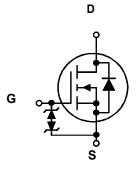
General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench[®] process that has been especially tailored to minimize the on-state resistance and switching loss. G-S zener has been added to enhance ESD voltage level.

Applications

- DC DC Conversion
- Inverter
- Synchronous Rectifier





MOSFET Maximum Ratings T_C = 25 °C unless otherwise noted

	Parameter				Ratings		Units	
Drain to	Drain to Source Voltage				100		V	
Gate to	Gate to Source Voltage				±20		V	
Drain Current -Continuous (Package limited) T _C = 25 °C					42		A	
-Continuous (Silicon limited) T _C = 25 °C					35			
-Continuous $T_A = 25 \degree C$ (Note 1a)				8				
-Pulsed					40			
Single F	Single Pulse Avalanche Energy (Note 3)				84		mJ	
Power Dissipation $T_{C} = 25 \text{ °C}$					54 3.1		W	
Power Dissipation $T_A = 25 \text{ °C}$ (Note 1a)								
Operating and Storage Junction Temperature Range				-55 to +150		°C		
		-			-		1	
Thermal Resistance, Junction to Case					2.3		°C/W	
Thermal Resistance, Junction to Ambient (Note 1a)				40		3,11		
arking a	nd Ordering Inform	ation						
arking	Device	Package	Re	eel Size	Tape Width	Qua	antity	
02LZ	FDD86102LZ	D-PAK(TO-252)	D-PAK(TO-252) 13 " 12 mm 25		2500	2500 units		
	Gate to Drain Cl Single F Power I Power I Operatin naracteri Therma arking a arking	Drain to Source Voltage Gate to Source Voltage Drain Current -Continuous (Pack -Continuous (Silico -Continuous -Continuous Single Pulse Avalanche Energy Power Dissipation Poperating and Storage Junction T naracteristics Thermal Resistance, Junction to A arking and Ordering Inform	Drain to Source Voltage Gate to Source Voltage Drain Current -Continuous (Package limited) T _C = -Continuous (Silicon limited) T _C = -Continuous T _A = -Pulsed Single Pulse Avalanche Energy Power Dissipation T _C = Power Dissipation T _C = Operating and Storage Junction Temperature Range naracteristics Thermal Resistance, Junction to Case Thermal Resistance, Junction to Ambient arking and Ordering Information arking Device	Drain to Source Voltage Gate to Source Voltage Drain Current -Continuous (Package limited) $T_C = 25 \ ^{\circ}C$ -Continuous (Silicon limited) $T_C = 25 \ ^{\circ}C$ -Continuous $T_A = 25 \ ^{\circ}C$ -Pulsed Single Pulse Avalanche Energy Power Dissipation $T_C = 25 \ ^{\circ}C$ Power Dissipation $T_C = 25 \ ^{\circ}C$ Operating and Storage Junction Temperature Range naracteristics Thermal Resistance, Junction to Case Thermal Resistance, Junction to Ambient arking and Ordering Information arking Device	Drain to Source Voltage Gate to Source Voltage Drain Current -Continuous (Package limited) $T_C = 25 \ ^{\circ}C$ -Continuous (Silicon limited) $T_C = 25 \ ^{\circ}C$ -Continuous $T_A = 25 \ ^{\circ}C$ -Continuous $T_A = 25 \ ^{\circ}C$ -Continuous $T_C = 25 \ ^{\circ}C$ Pulsed (Note 3) Power Dissipation $T_C = 25 \ ^{\circ}C$ Power Dissipation $T_A = 25 \ ^{\circ}C$ Operating and Storage Junction Temperature Range haracteristics Thermal Resistance, Junction to Case Thermal Resistance, Junction to Ambient (Note 1a) arking and Ordering Information arking Device	Drain to Source Voltage100Gate to Source Voltage ± 20 Drain Current -Continuous (Package limited) $T_C = 25 \ ^{\circ}C$ 42 -Continuous (Silicon limited) $T_C = 25 \ ^{\circ}C$ 35 -Continuous (Silicon limited) $T_C = 25 \ ^{\circ}C$ 35 -Continuous $T_A = 25 \ ^{\circ}C$ 40 Single Pulse Avalanche Energy(Note 3) 84 Power Dissipation $T_C = 25 \ ^{\circ}C$ 54 Power Dissipation $T_C = 25 \ ^{\circ}C$ 54 Power Dissipation $T_A = 25 \ ^{\circ}C$ 40	Drain to Source Voltage100Gate to Source Voltage ± 20 Drain Current -Continuous (Package limited) $T_C = 25 \ ^{\circ}C$ 42-Continuous (Silicon limited) $T_C = 25 \ ^{\circ}C$ 35-Continuous (Silicon limited) $T_C = 25 \ ^{\circ}C$ 35-Continuous $T_A = 25 \ ^{\circ}C$ (Note 1a)Single Pulse Avalanche Energy(Note 3)84Power Dissipation $T_C = 25 \ ^{\circ}C$ 54Power Dissipation $T_A = 25 \ ^{\circ}C$ 54Power Dissipation $T_A = 25 \ ^{\circ}C$ 54Power Dissipation $T_A = 25 \ ^{\circ}C$ 54Power DissipationT_A = 25 \ ^{\circ}C54Power DissipationT_A = 25 \ ^{\circ}C54Power DissipationT_A = 25 \ ^{\circ}C54Power DissipationT_A = 25 \ ^{\circ}C100Maracteristics2.3100Thermal Resistance, Junction to Case2.3Thermal Resistance, Junction to Ambient(Note 1a)Arking and Ordering Information40arkingDevicePackageReel SizeTape WidthQuartering Case	

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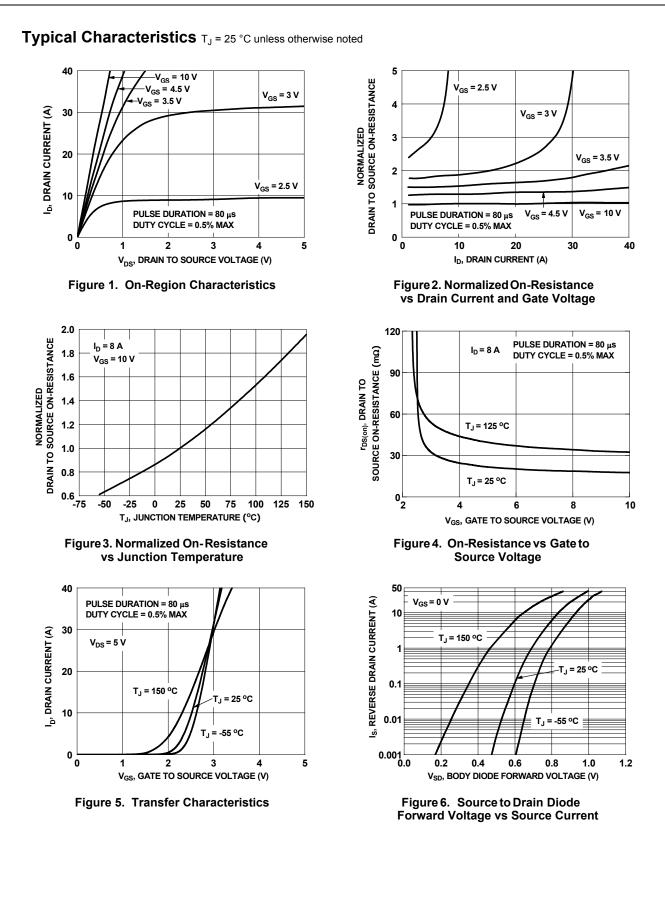
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	I _D = 250 μA, V _{GS} = 0 V	100			V
ABV _{DSS}	Breakdown Voltage Temperature					
ΔT_J	Coefficient	I_D = 250 $\mu A,$ referenced to 25 $^\circ C$		69		mV/°C
DSS	Zero Gate Voltage Drain Current	V _{DS} = 80 V, V _{GS} = 0 V			1	μA
GSS	Gate to Source Leakage Current	V _{GS} = ±20 V, V _{DS} = 0 V			±10	μA
On Chara	ICTERISTICS (Note 2)					
V _{GS(th)}	Gate to Source Threshold Voltage	V _{GS} = V _{DS} , I _D = 250 μA		1.5	3.0	V
$\Delta V_{GS(th)}$	Gate to Source Threshold Voltage		1.0			24/20
ΔT_J	Temperature Coefficient	I_D = 250 $\mu A,$ referenced to 25 $^\circ C$		-6		mV/°C
r _{DS(on)} St		V _{GS} = 10 V, I _D = 8 A		17.8	22.5	mΩ
	Static Drain to Source On Resistance	V _{GS} = 4.5 V, I _D = 7 A		23.2	31	
		V _{GS} = 10 V, I _D = 8 A, T _J = 125 °C		31.1	40	
FS	Forward Transconductance	V _{DS} = 5 V, I _D = 8 A		31		S
Dvnamic	Characteristics					
C _{iss}	Input Capacitance			1157	1540	pF
Coss	Output Capacitance	$V_{\rm DS} = 50 \text{ V}, V_{\rm GS} = 0 \text{ V},$		181	245	pF
Srss	Reverse Transfer Capacitance	f = 1 MHz		7.7	15	pF
R _g	Gate Resistance			0.6		Ω
	g Characteristics			0.0		
d(on)	Turn-On Delay Time			6.6	14	ns
r	Rise Time	$V_{DD} = 50 \text{ V}, \text{ I}_{D} = 8 \text{ A},$		2.3	10	ns
d(off)	Turn-Off Delay Time	V _{GS} = 10 V, R _{GEN} = 6 Ω		20	32	ns
f	Fall Time			2.3	10	ns
ζ _g	Total Gate Charge	$V_{GS} = 0 V \text{ to } 10 V$		18	26	nC
ζ _g	Total Gate Charge	$V_{GS} = 0 V \text{ to } 4.5 V V_{DD} = 50 V,$		8.7	13	nC
ୁ C _{gs}	Gate to Source Gate Charge	I _D = 8 A		2.7		nC
ସୁ _{gd}	Gate to Drain "Miller" Charge			2.4		nC
Drain-So	urce Diode Characteristics					
V _{SD} Source		$V_{GS} = 0 V, I_S = 8 A$ (Note 2)		0.82	1.3	V
	Source to Drain Diode Forward Voltage			0.75	1.2	
rr	Reverse Recovery Time			43	70	ns
ე ^ლ	Reverse Recovery Charge	$I_{\rm F} = 8$ A, di/dt = 100 A/µs		43	70	nC
Drain-So V_{SD} t_{rr} Q_{rr} Notes: 1. R _{0JA} is the su	Source to Drain Diode Forward Voltage Reverse Recovery Time	$V_{GS} = 0 V$, $I_S = 2.6 A$ (Note 2) $I_F = 8 A$, di/dt = 100 A/µs tance where the case thermal reference is defined	as the solde	0.75 43 43	1.2 70 70	e dra

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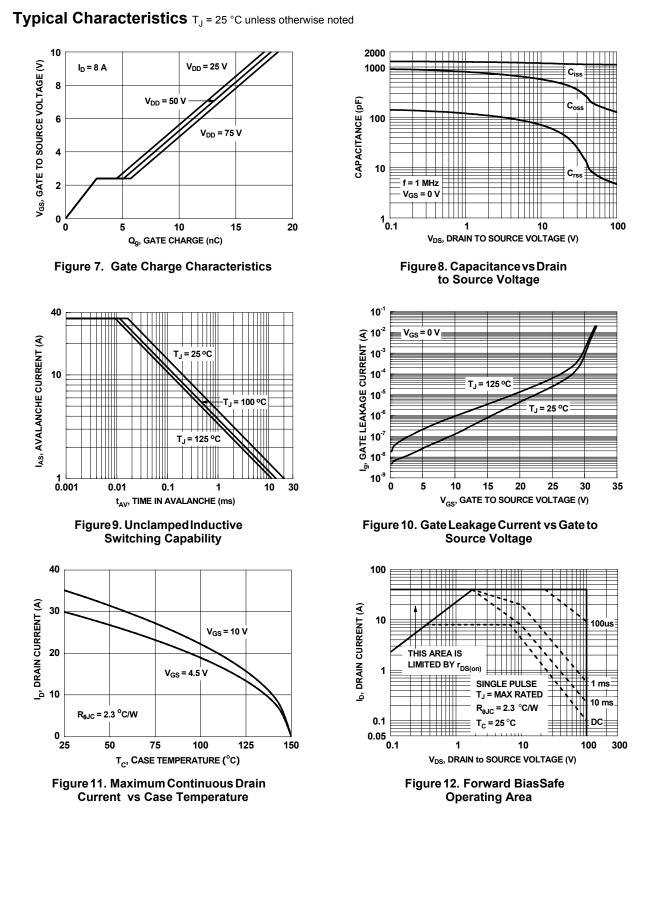
2. Pulse Test: Pulse Width < 300 $\mu s,$ Duty cycle < 2.0%.

3. Starting $T_J = 25^{\circ}C$, L = 1 mH, $I_{AS} = 13$ A, $V_{DD} = 90$ V, $V_{GS} = 10$ V.

4. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

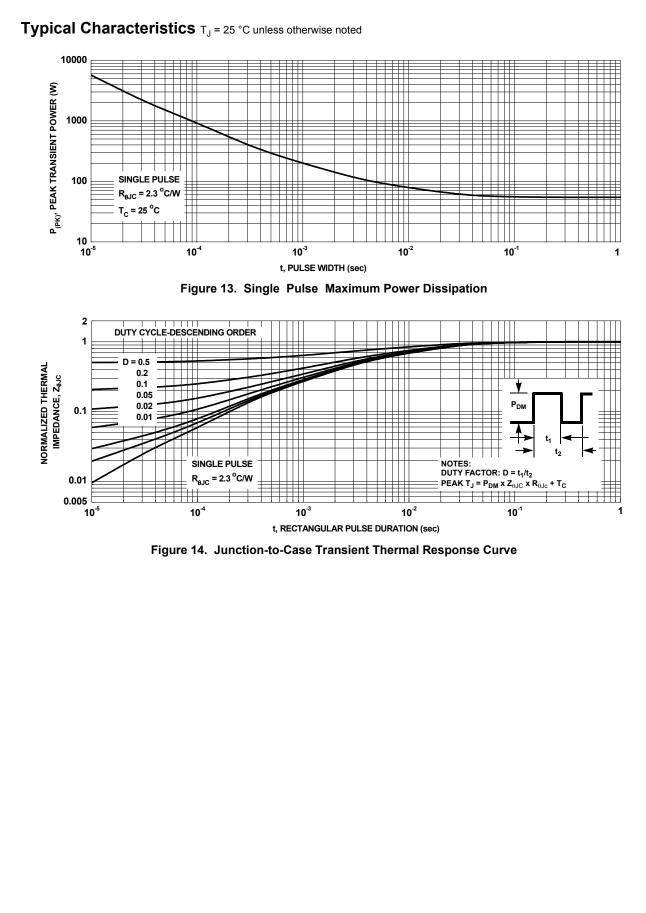


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